

Turning Test Information Into Knowledge

Galaxy's Examiner

- Wicked Fast
- Originally Powerful
- Wonderfully Simple

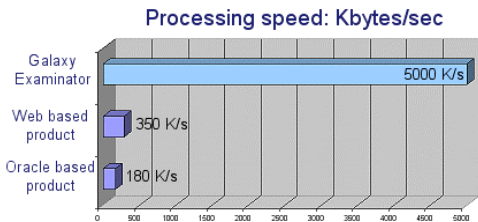
What is Examiner?

Examiner, formed from the contraction of EXAMINE and transLATOR, is a software solution, which turns test data files such as STDF (Standard Test Data Format) or ATDF into canned HTML reports so that test and product engineers can perform characterization and yield analysis studies rapidly and efficiently.

Design Principles

Galaxy has applied its usual design principles to Examiner by placing ourselves in the user's shoes. We had one goal in mind: make this tool a 'Single Click' solution so users would only be one mouse click away from the meaningful report they want.

Who are our users? Product engineers and test engineers mainly. Senior and junior. What do they want? Typically, these engineers will conduct characterization and yield analysis studies in the early stages of a device launch. Hence, when it comes to drilling down into millions of data points, and play *what if* scenarios for example, response time is critical.



Note: Trials done on databases of 60Mega bytes or more to ensure measurement accuracy. On smaller

databases, the query response time of Galaxy Examiner was way too fast to compare!

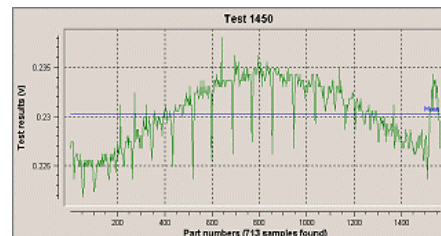
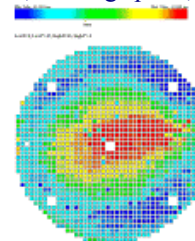


In a nutshell, Examiner is designed to be *wicked fast* and *wonderfully easy to use*.

Examiner's Main Features

Reports:

- Global information: tester, lot, operator information
- Yield information: good parts, failing parts, parts retested.
- Test summary: Cp, Cpk, mean, sigma.
- Parametric test wafer map: analyze the test gradient on your wafer to investigate process problems.
- Test histogram: quickly view your test distribution!
- Wafer map: see all dies tested in production, time info, etc.
- Parametric Trend charts: see how test results evolve over time in production.



- Correlation reports and charts.

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